



TEST REPORT IEC 60947-2

Low-voltage switchgear and controlgear - Part 2: Circuit-breakers

Date of issue: 2024-02-26

Total number of pages...... 138

Name of Testing Laboratory Shanghai Testing & Inspection Institute for Electrical Equipment

preparing the Report...... Co.,Ltd. (STIEE)

Applicant's name Zhejiang Tengen Electric Co., Ltd.

P.R.China

Test specification:

Standard.....: IEC 60947-2:2016, IEC 60947-2:2016/AMD1:2019, for use in

conjunction IEC 60947-1:2007, IEC 60947-1:2007/AMD1:2010,

IEC 60947-1:2007/AMD2:2014

Test procedure: CB Scheme

Non-standard test method: N/A

Test Report Form No.: IEC60947_2K

Test Report Form(s) Originator: DEKRA Certification B.V.

Master TRF.....: Dated 2023-09-14

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Report No. 00901-CB2021CQC-098591

Test item description:	Mould	ed Case Circuit-breakers	
Trade Mark(s):	TENG	GEN	
Manufacturer:	Sulv Ir	ng Tengen Electric Co., Ltd. ndustrial Area, Liushi Town, Yueqing (ice, P.R.China	City, Zhejiang
TGM1		E□-400L,TGM1E□-400Y,TGM1E□-400M, E□-400H,TGM3E□-400L,TGM3E□-400Y, E□-400M,TGM3E□-400H	
Ratings: See pa		age 25	
Describle Testion Lebergton (see anniherble) testion massed on and testion Leastion (s)			
Responsible Testing Laboratory (as applicable), testing procedure and testing location(s):			
		Shanghai Testing & Inspection Institute for Electrical Equipment Co.,Ltd.(STIEE)	
Testing location/ address:		505 Wu Ning Rd. Shanghai 200063, P.R. CHINA	
Tested by (name, function, signature):		Liu Wei/Engineer	过滤
Approved by (name, function, signature):		Yin Jifu/Senior engineer	倒去福
☐ Testing procedure: CTF Stage 1		T	
Testing location/ address:			
Tested by (name, function, signature):			
Approved by (name, function, signature):			
		T	
Testing procedure: CTF Stage 2:			
Testing location/ address:			
Tested by (name + signature):			
Witnessed by (name, function, signature).:			
Approved by (name, function, signature):			
		T	
Testing procedure: CTF Stage 3:			
Testing procedure: CTF Stage 4:			
Testing location/ address:			
Tested by (name, function, signature):			
Witnessed by (name, function, signature).:			
Approved by (name, function, signature):			
Supervised by (name, function, signature) :			